

Abstracts

Partially prism-gridded FDTD analysis for layered structures of transversely curved boundary

Chieh-Tsao Hwang and Ruey-Beei Wu. "Partially prism-gridded FDTD analysis for layered structures of transversely curved boundary." 1998 MTT-S International Microwave Symposium Digest 98.3 (1998 Vol. III [MWSYM]): 1417-1420.

A partially prism-gridded FDTD analysis is presented to deal with layered structures with curved boundary in transverse directions. It is applied to calculate the scattering parameters of vias in multilayer packaging. The good agreement of the results with those by other methods verifies the accuracy of this analysis.

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